

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/827,072	KUMAR ET AL.	
Examiner	Art Unit	
Dah-Wei D. Yuan	1745	

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	SEARCHED					
Class	Subclass	Date	Examiner			
429	231.3,224	6/5/2007	DWY			
427	122-124	6/5/2007	DWY			

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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	CH NOTES EARCH STRATEG	Y)
	DATE	EXMR
EAST	6/5/2007	DWY
STN	6/5/2007	DWY
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